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# Development of $2\pi$ Total Spectral Radiant Flux Standards at NIST

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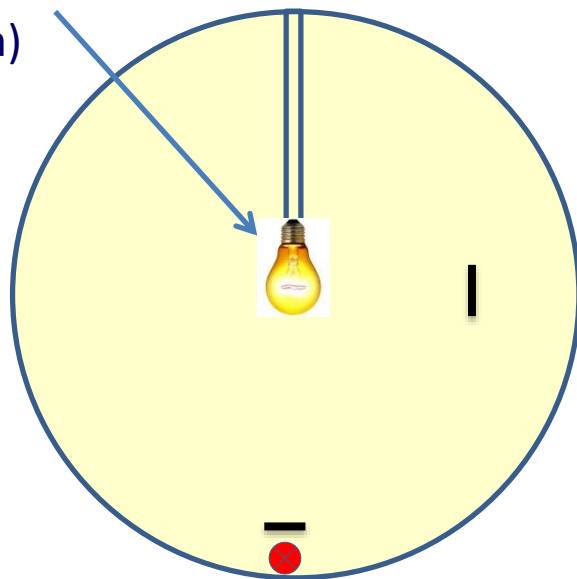
National Institute of Standards and Technology  
Gaithersburg, Maryland

# Outline

1. Introduction
2. Method for realization of total spectral radiant flux (TSRF) scale
3. Development of TSRF standards
  - $4\pi$  TSRF standard
  - $2\pi$  TSRF standard
4. Summary

# 4π sphere-spectroradiometer system

4π TSRF  
standard  
(W/nm)



4π test  
SSL products

Spectroradiometer

$\Rightarrow \Phi_{e,\lambda}(\lambda)$

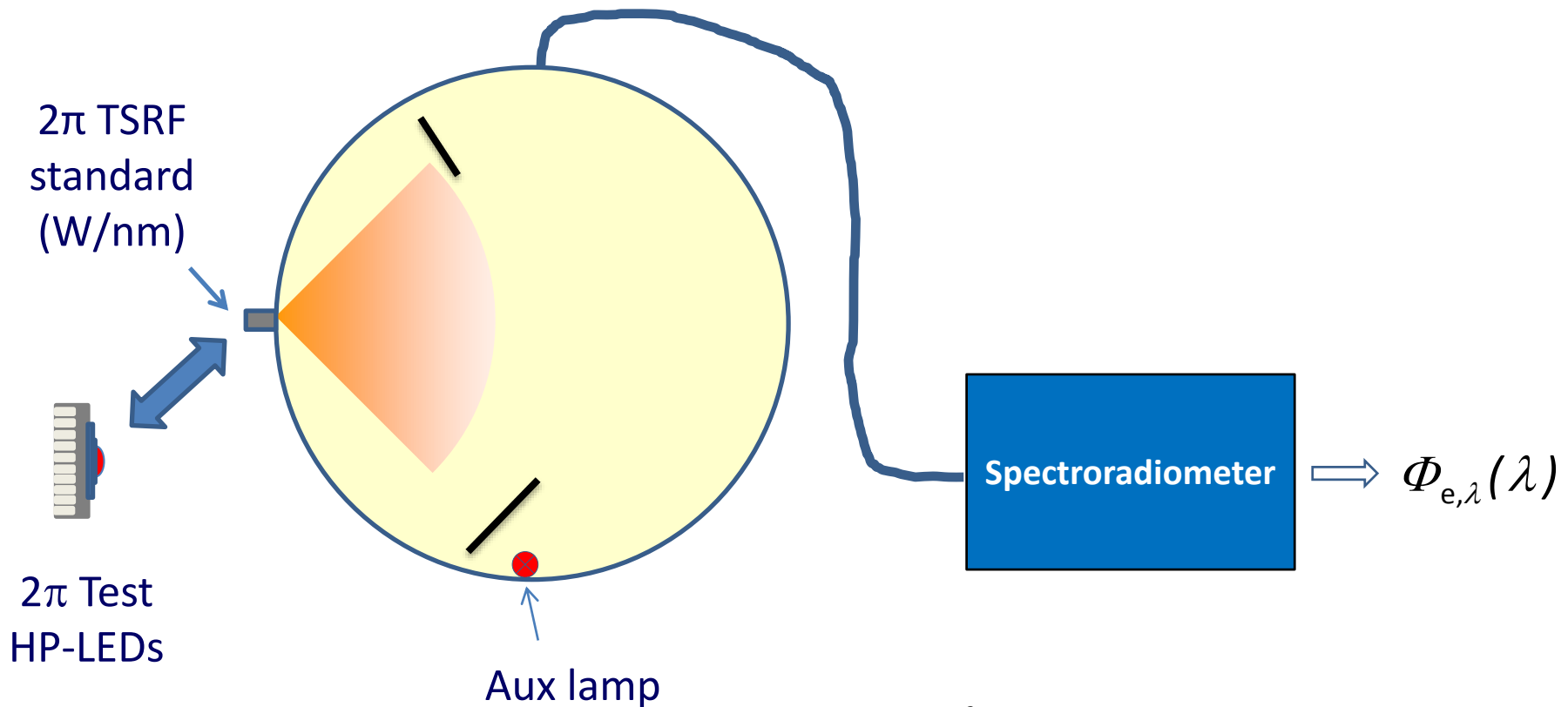
Aux lamp

$$\Phi_v = K_m \int_{\lambda} \Phi_{e,\lambda}(\lambda) V(\lambda) d\lambda$$

$K_m = 683 \text{ lm/W}$

$V(\lambda)$ : CIE spectral luminous efficiency function

# 2π sphere-spectroradiometer system



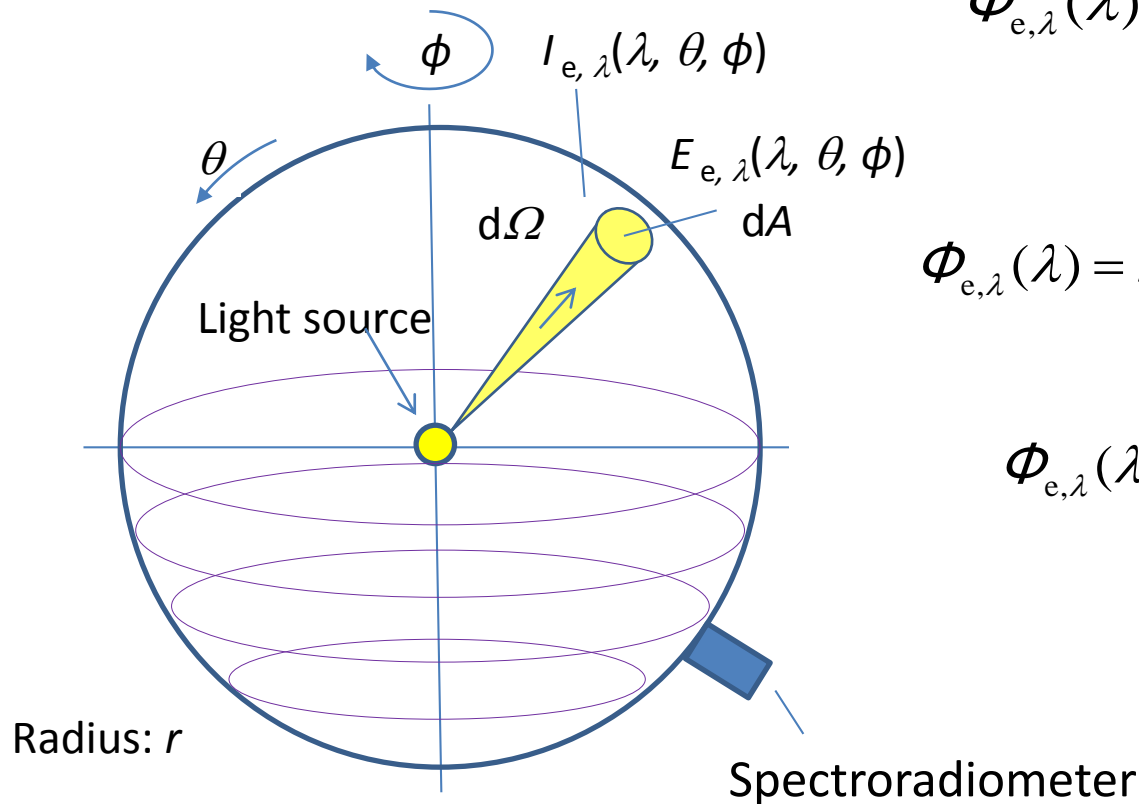
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$K_m = 683 \text{ lm/W}$

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# Realization of the TSRF scale

Measure spectral radiant intensity or spectral irradiance of a test lamp in many directions  $(\theta, \phi)$  using an absolute **gonio-spectroradiometer**.



$$\Phi_{e,\lambda}(\lambda) = \int_{\phi=0}^{2\pi} \int_{\theta=0}^{\pi} I_{\lambda}(\lambda, \theta, \phi) \sin \theta d\theta d\phi$$

or

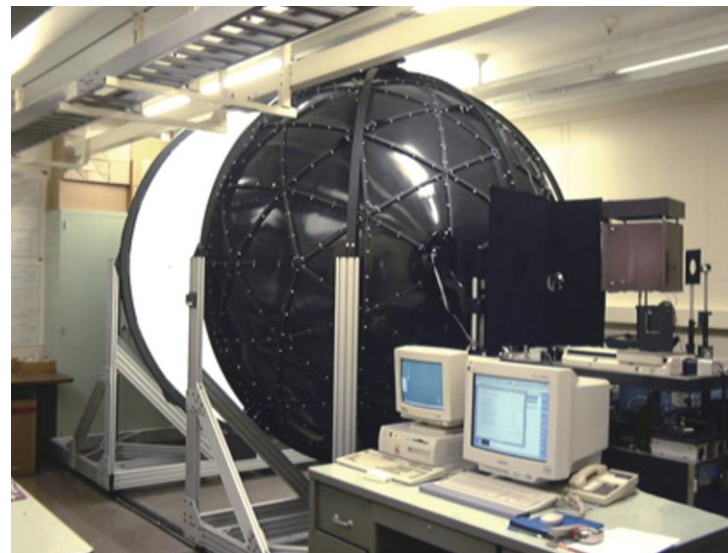
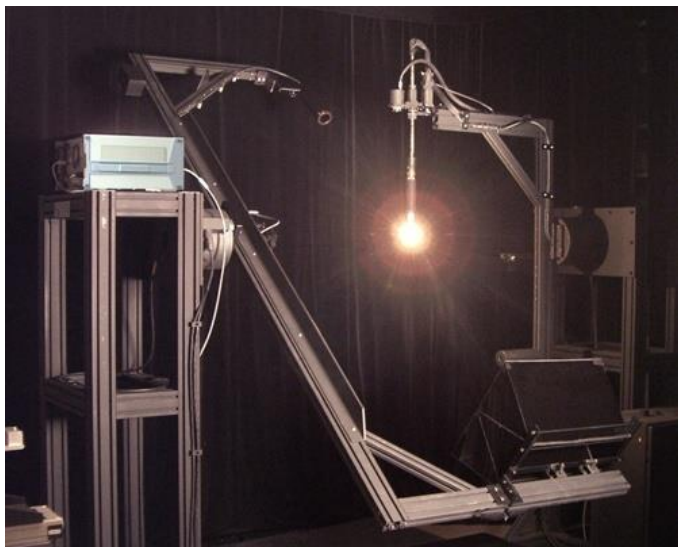
$$\Phi_{e,\lambda}(\lambda) = r^2 \int_{\phi=0}^{2\pi} \int_{\theta=0}^{\pi} E_{\lambda}(\lambda, \theta, \phi) \sin \theta d\theta d\phi$$

$\Phi_{e,\lambda}(\lambda)$ : total spectral radiant flux (W/nm)

However, an absolute gonio-spectroradiometer is costly!

# Realization of TSRF scale at NIST

Relative gonio-spectroradiometer    Absolute 2.5 m integrating sphere



Two-step approach, based on both

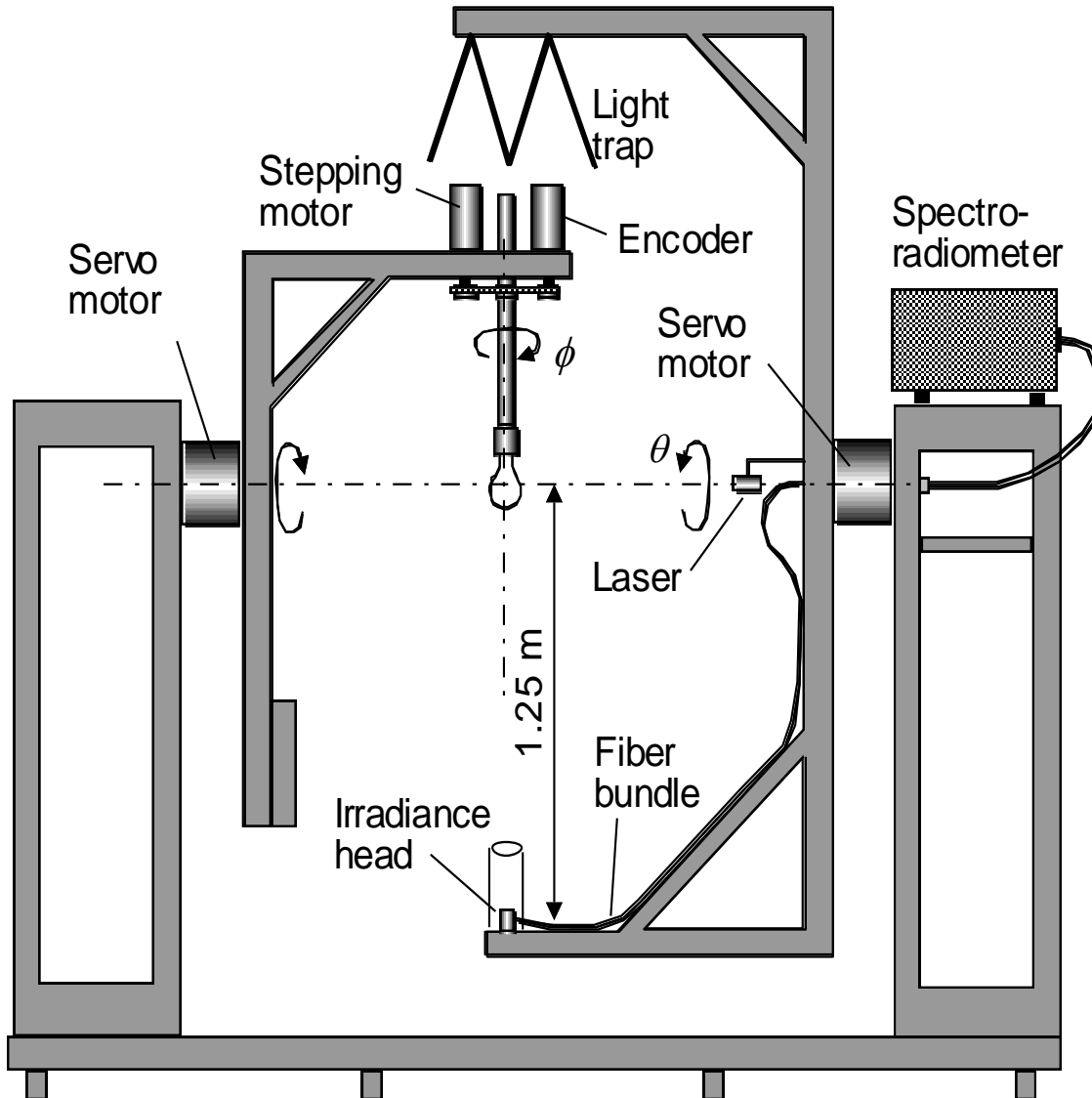
- Candela scale
- Spectral irradiance scale

$$k_{\text{scale}} = \frac{\Phi_v}{K_m \int_{\lambda=0}^{\infty} V(\lambda) \int_{\phi=0}^{2\pi} \int_{\theta=0}^{\pi} S(\lambda, \theta, \phi) \sin \theta \, d\theta \, d\phi \, d\lambda}$$

$$\Phi_{e,\lambda}(\lambda) = k_{\text{scale}} \int_{\phi=0}^{2\pi} \int_{\theta=0}^{\pi} S(\lambda, \theta, \phi) \sin \theta \, d\theta \, d\phi$$

Zong Y. and Ohno Y., Realization of total spectral radiant flux scale and calibration service at NIST, in Proc. CIE, July 4-11, 2007, Beijing, China, CIE 178:2007, D2-179 to D2-182. (2007)

# The relative gonio-spectroradiometer



Rotation radius:  
1.25 m

Angle coverage  
 $3^\circ \leq \theta \leq 180^\circ$   
 $0^\circ \leq \phi \leq 360^\circ$

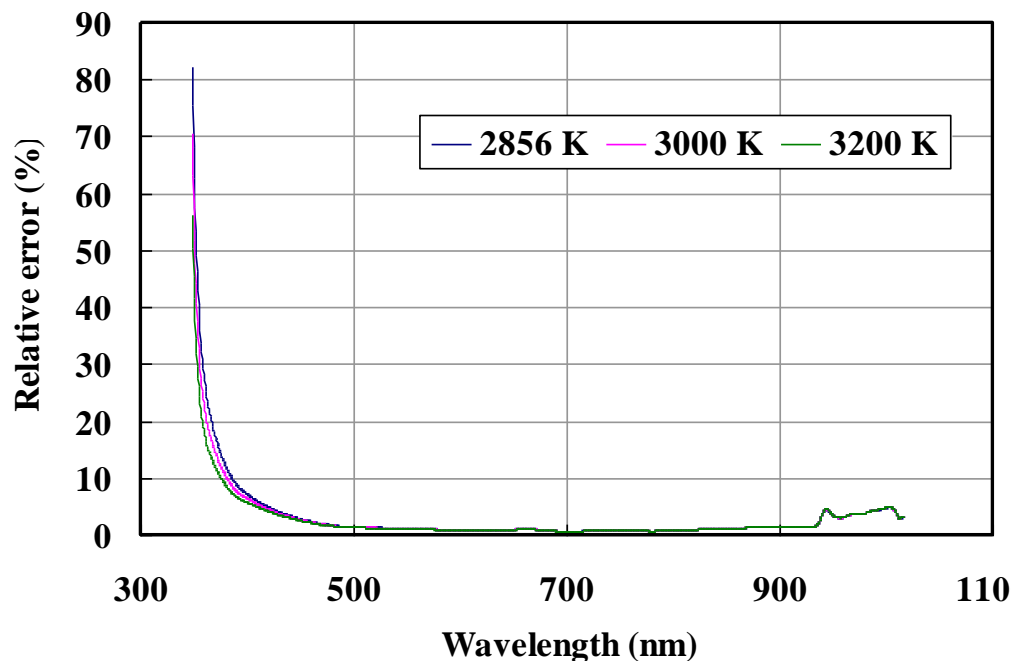
Spectroradiometer:  
CCD array system  
(300 nm - 1100 nm)

Speed:  
1 hour per scan with  
 $10^\circ$  step

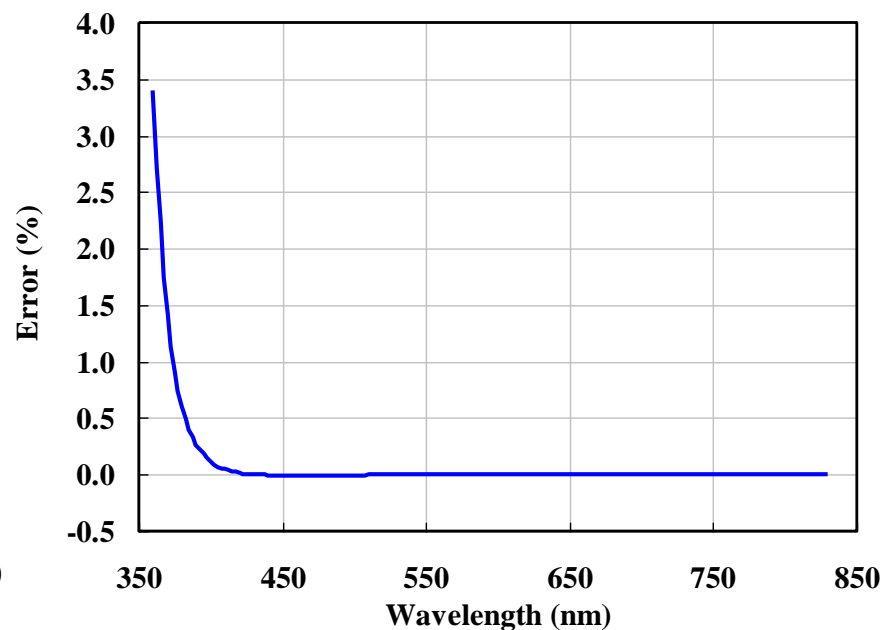
**Stray light is serious  
in NIR! Good  
baffling is critical.**

# Stray-light correction for the spectroradiometer

## Stray-light error vs lamp CCT

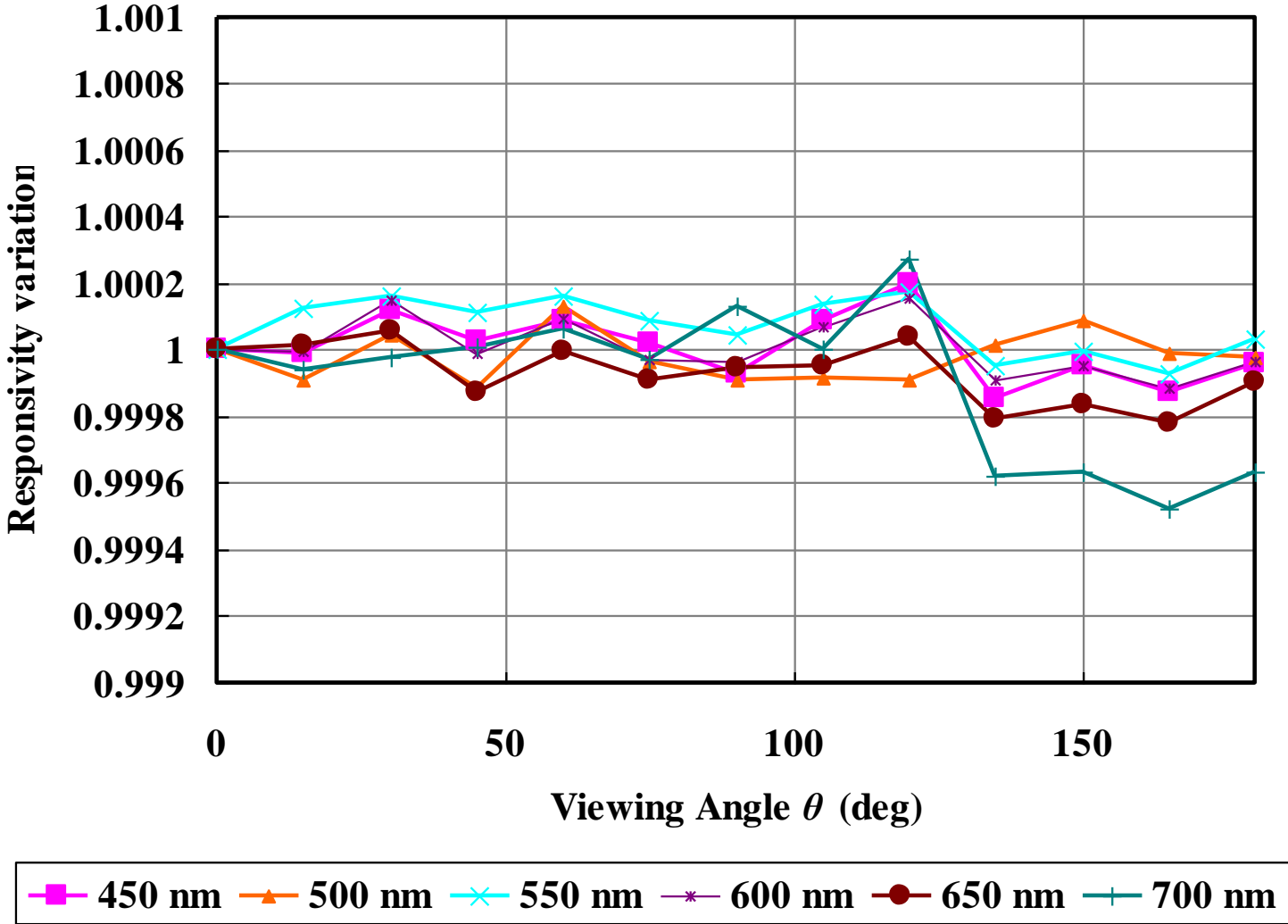


## Stray-light error in calibration results (for a 3200 K test lamp)

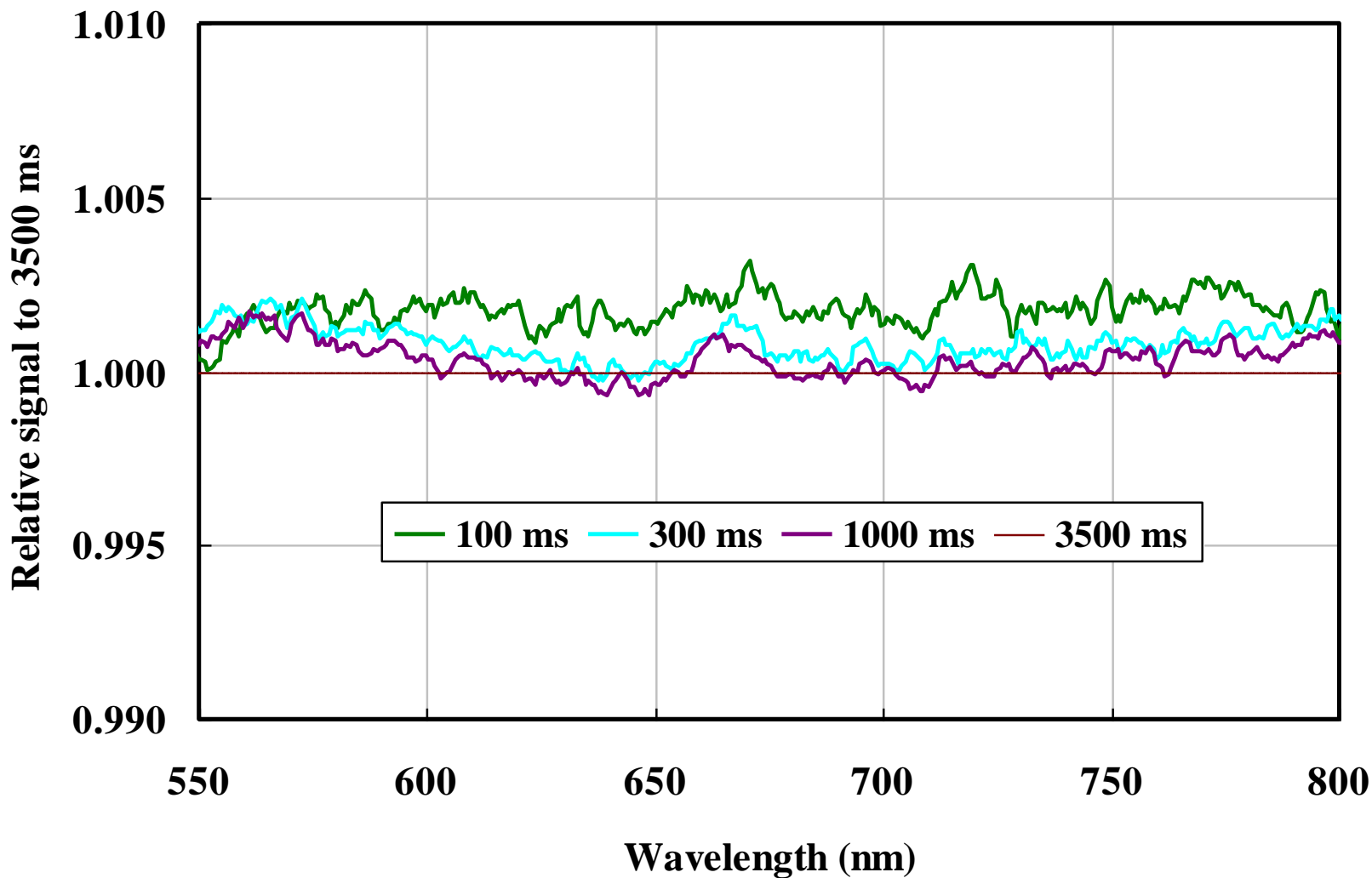




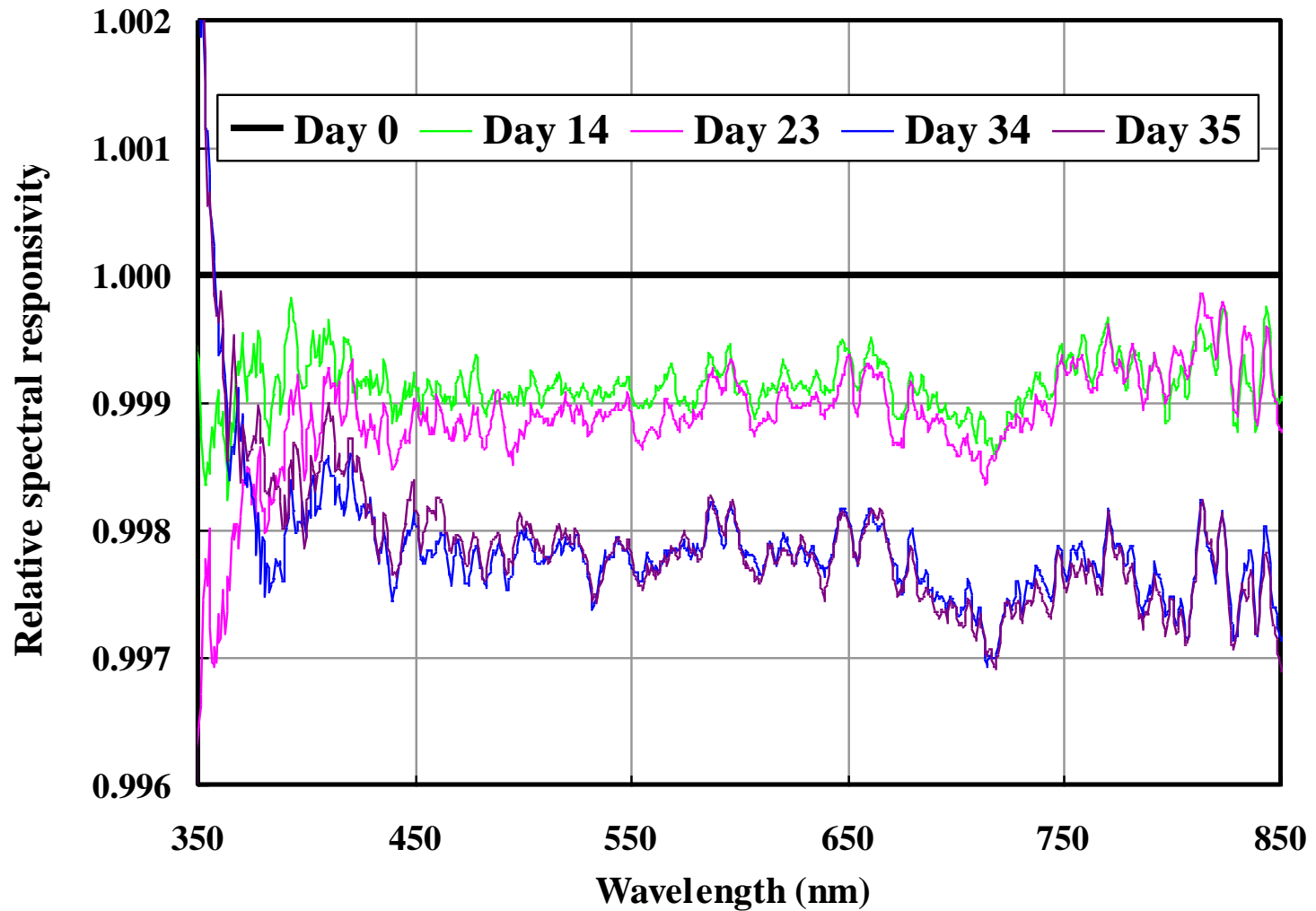
# Spectral responsivity vs viewing angle



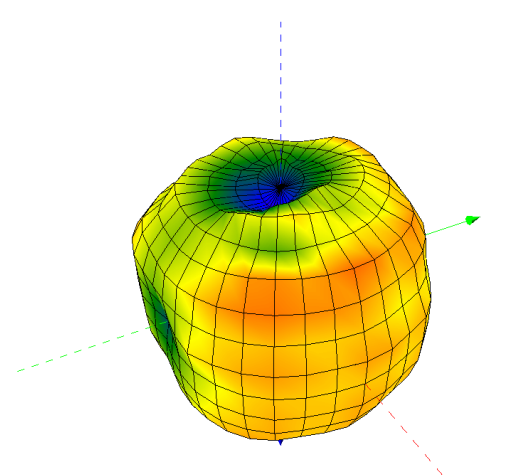
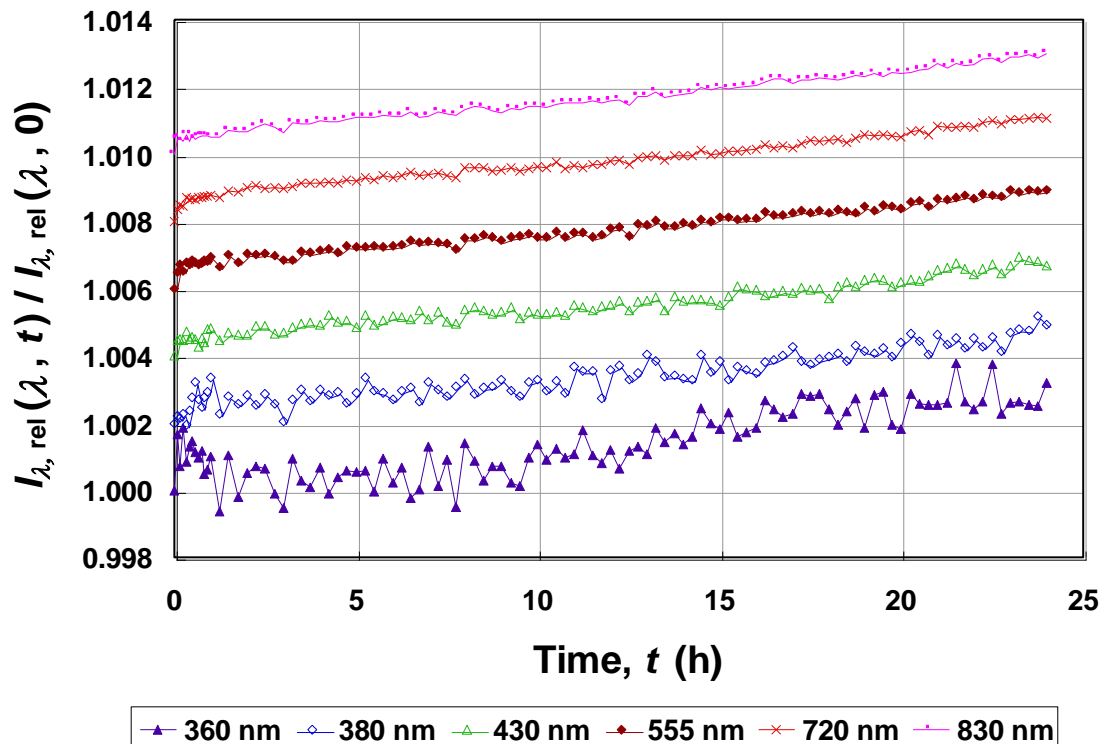
# Signal nonlinearity of the array spectroradiometer



# Stability of the gonio-spectroradiometer



# 4π TSRF standard



Aging curves of radiant intensity at 3100 K CCT at six wavelengths.

## NIST 4π TSRF standard

- 75 W, 28 V, 3100 K QTH lamp
- First developed in 2006

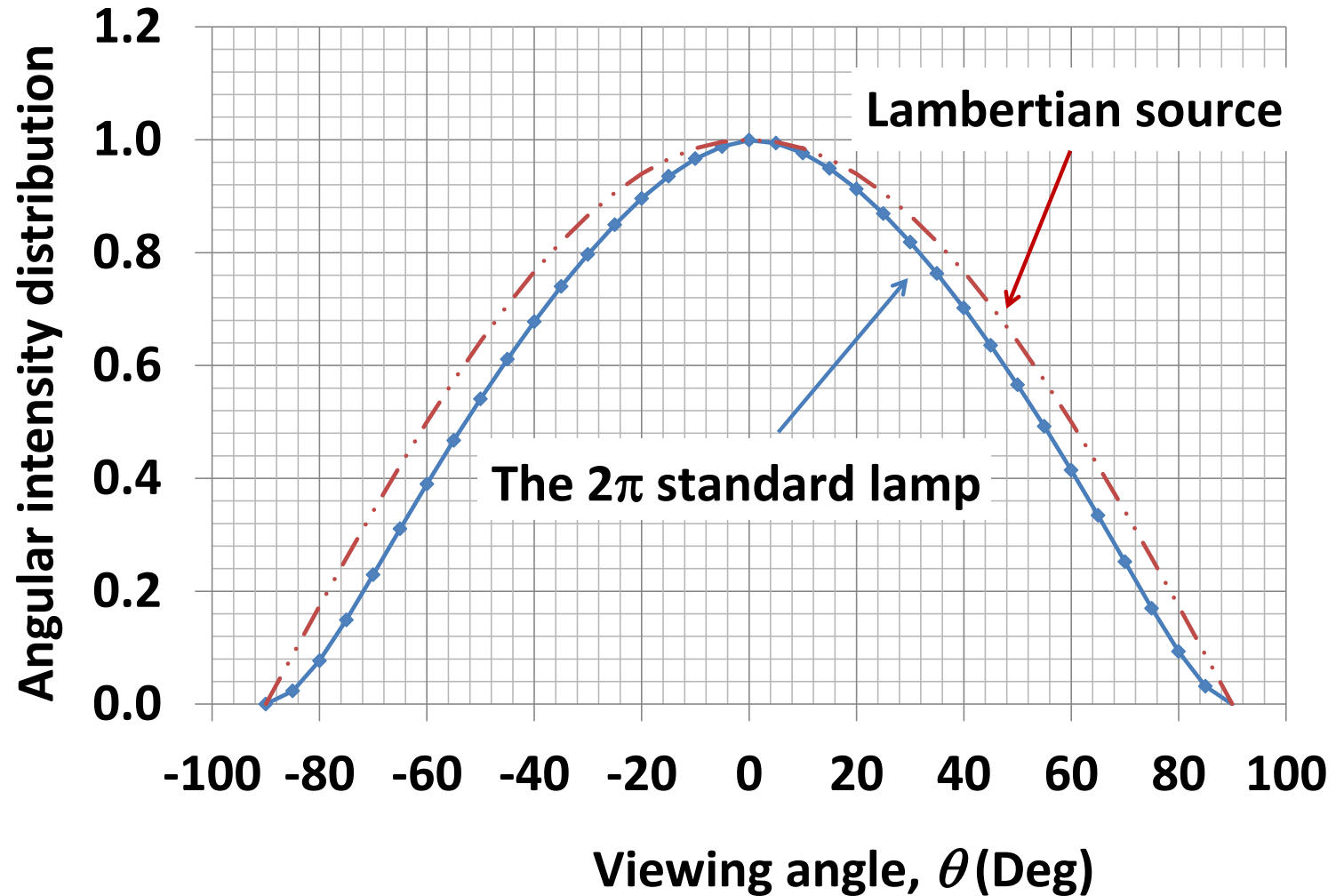
# The newly developed $2\pi$ TSRF standard



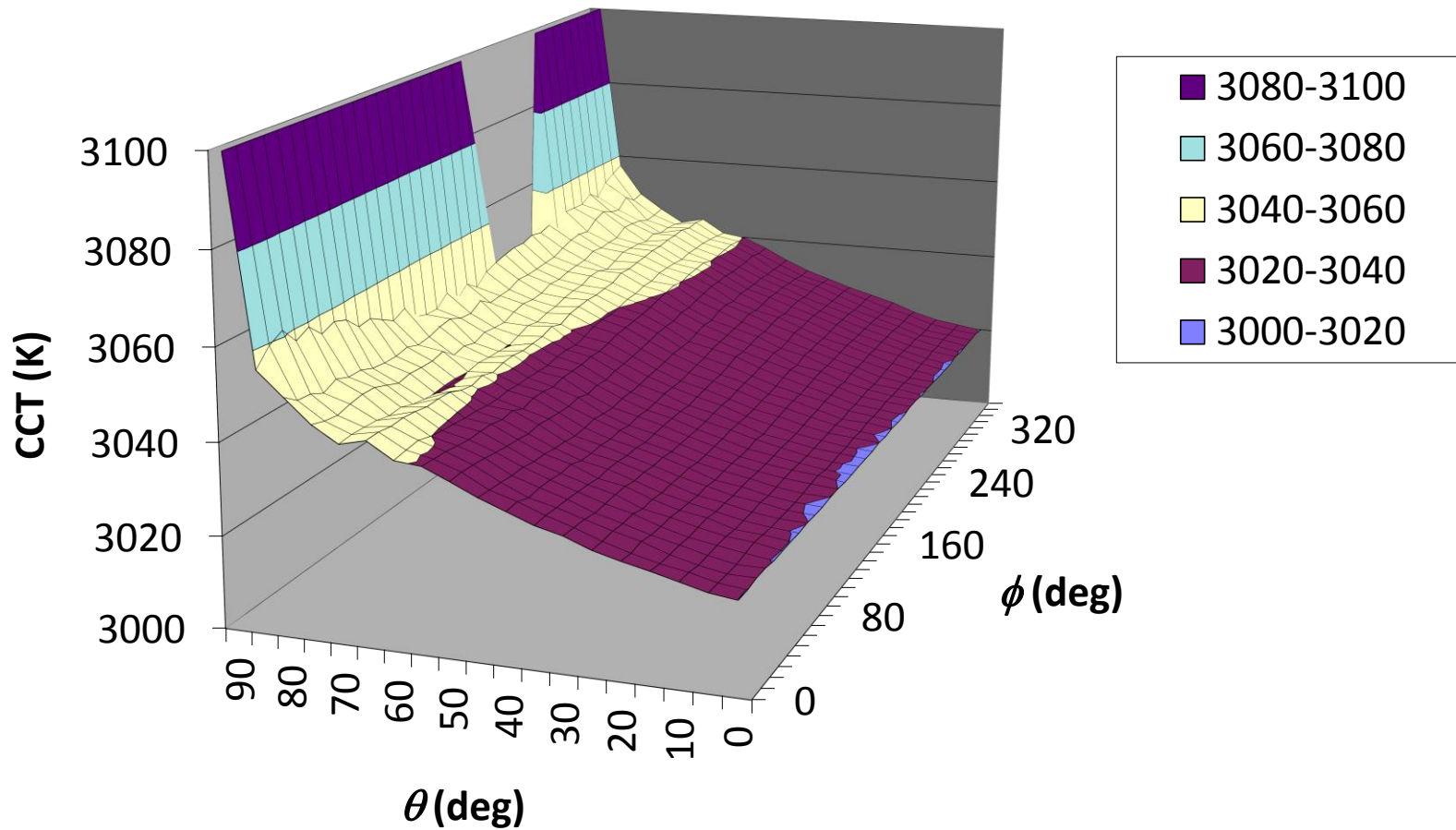
## First $2\pi$ standard

- 20 W, 12 V, 3000 K reflector halogen lamp
- Modified for a near Lambertian beam pattern

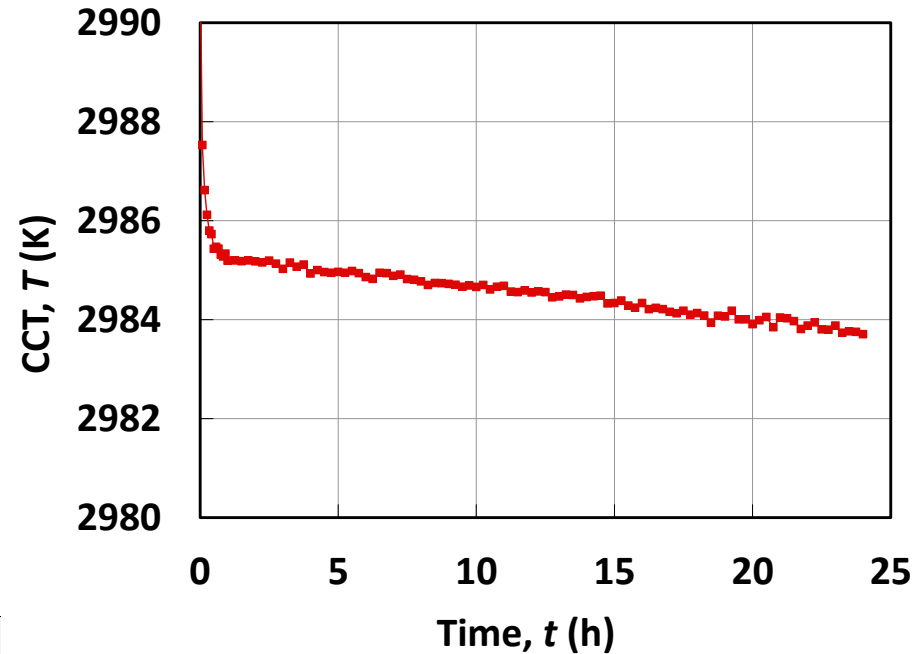
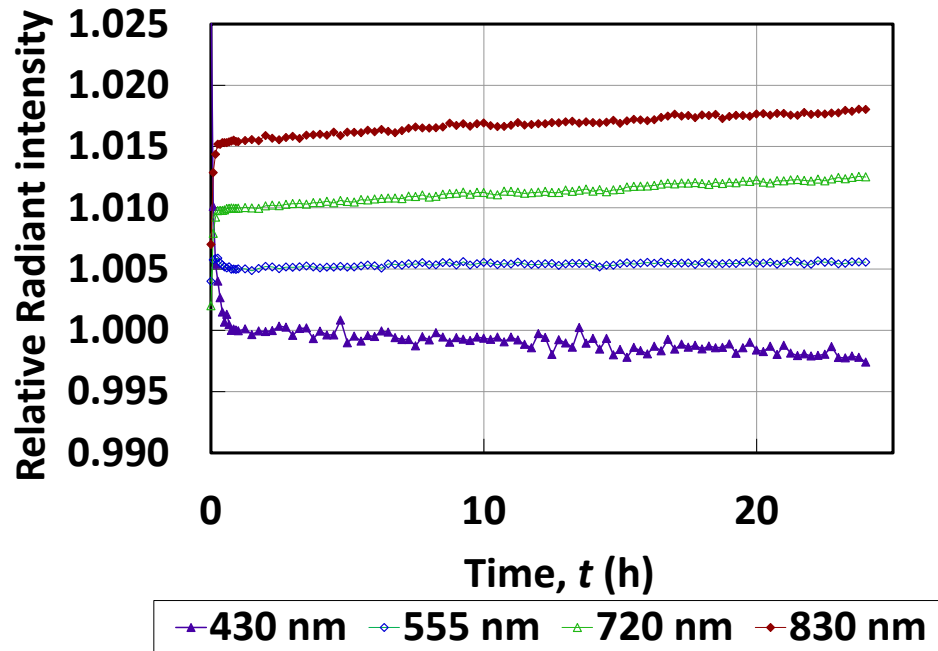
# Measured beam profile of the $2\pi$ TSRF standard



# Measured CCT of the $2\pi$ TSRF standard



# Aging rate of the $2\pi$ TSRF lamp

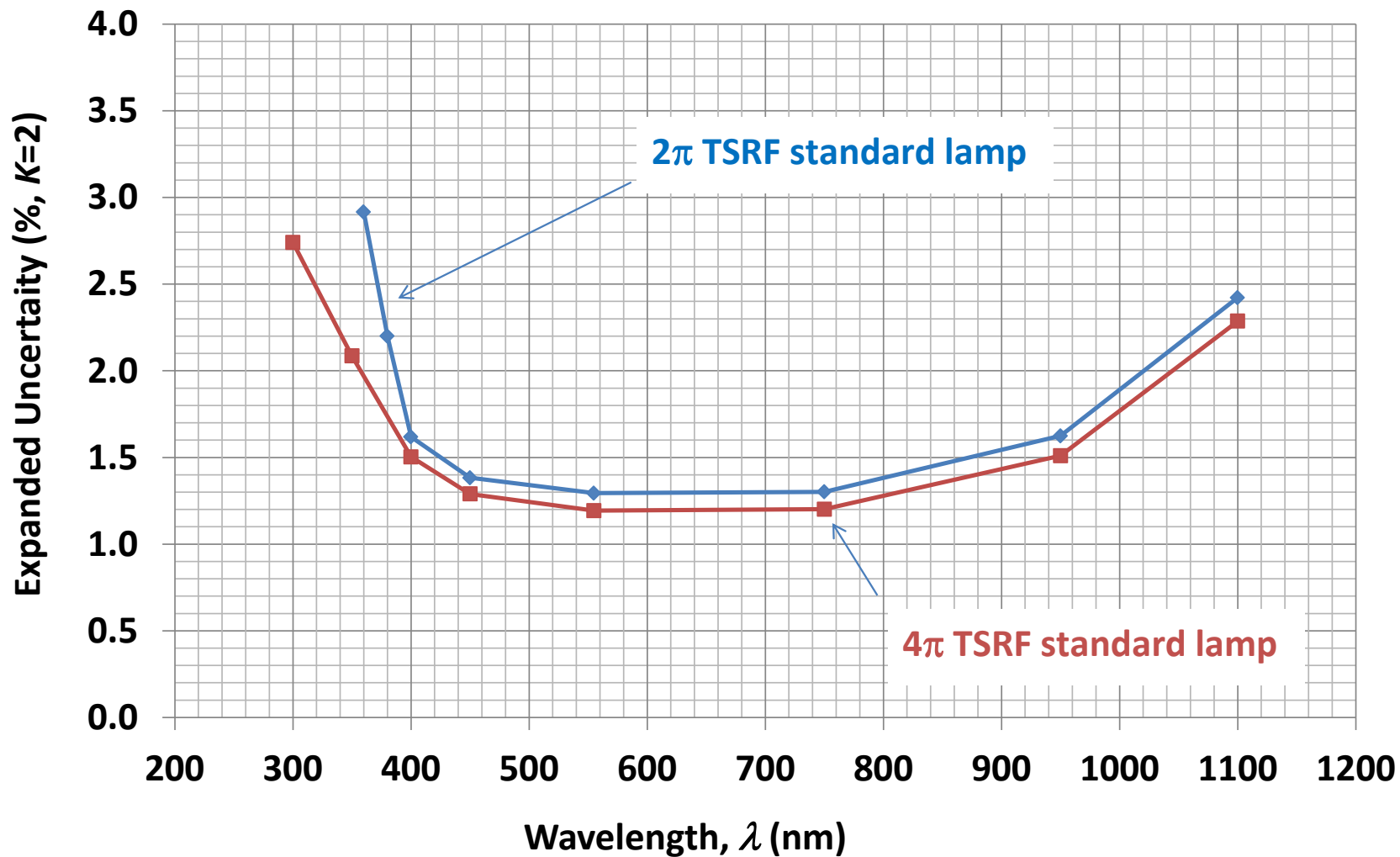


Aging curves of spectral radiant intensity at 430 nm, 555 nm, 720 nm, and 830 nm over 24 h operation time.

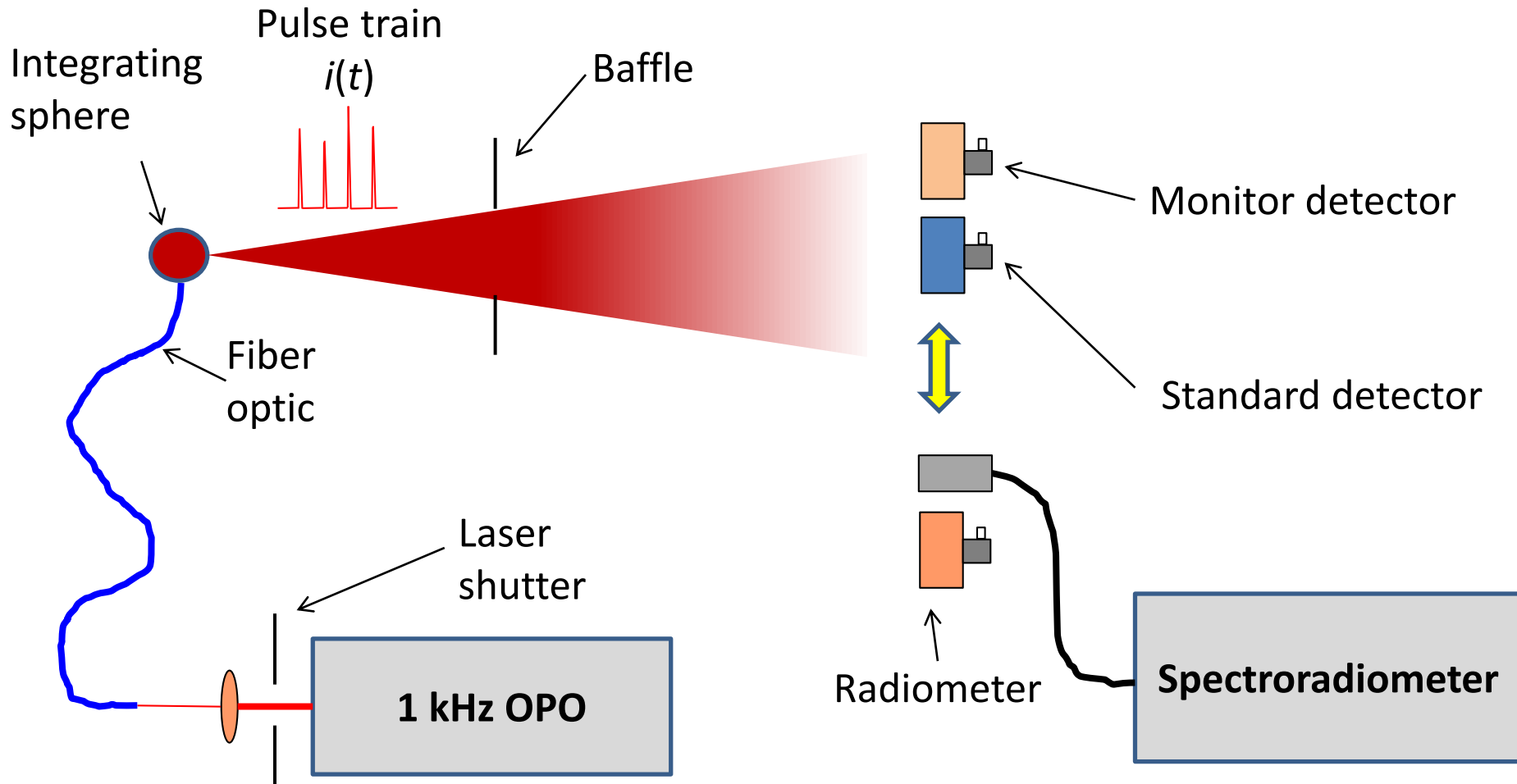
Aging of CCT over 24 h operation time



# Uncertainty of NIST TSRF standard lamps



# Calibration of sensors using tunable kHz OPO



- Use energy mode (dose) instead of power mode.
- Use charge amplifiers instead of trans-impedance amplifiers.
- 10 ppm repeatability with >20 % laser power fluctuations.

# Summary

- NIST has developed a new  $2\pi$  total spectral radiant flux calibration standard from 360 nm to 1100 nm with uncertainty between 2.9 % to 1.3 % ( $k=2$ ), using a relative gonio-spectroradiometer, based on the NIST total luminous flux scale and the NIST spectral irradiance scale.
- The calibration service is available for either submitted lamps or NIST issued new lamps.
- Research is still going on to
  - 1) Improve the facility of further reducing uncertainties.
  - 2) Extend to the spectral range to deep UV.

# References

[1] ZONG, Y. and OHNO, Y. 2007. Realization of total spectral radiant flux scale and calibration service at NIST. CIE 26th Session – Beijing 2007, D2 179-182.

[2] OHNO, Y. and ZONG, Y. 1999. Detector-Based Integrating Sphere Photometry, Proc., 24th Session of the CIE, 1999, 1, Part 1, 155-160.

[3] YOON, H. W., GIBSON, C. E., and BARNES, P. Y. 2002. Realization of the National Institute of Standards and Technology detector-based spectral irradiance scale, Appl. Opt., 2002, 41, 5879-5890.

[4] ZONG, Y., BROWN, S. W., JOHNSON, B. C., LYKKE, K. R., and OHNO, Y. 2006. Simple spectral stray light correction method for array spectroradiometers, Appl. Opt., 2006, 45, 1111-1119.

**Thank you**

